

PCN# : P64EAAB Issue Date : Jun. 01, 2016

DESIGN/PROCESS CHANGE NOTIFICATION

This is to inform you that a change is being made to the products listed below.

Unless otherwise indicated in the details of this notification, the identified change will have no impact on product quality, reliability, electrical, visual or mechanical performance and affected products will remain fully compliant to all published specifications. Products incorporating this change may be shipped interchangeably with existing unchanged products.

This change is planned to take effect in 90 calendar days from the date of this notification. Please work with your local Fairchild Sales Representative to manage your inventory of unchanged product if your evaluation of this change will require more than 90 calendar days.

Please contact your local Customer Quality Engineer within 30 days of receipt of this notification if you require any additional data or samples.

Implementation of change:

Expected First Shipment Date for Changed Product : Aug. 30, 2016

Expected First Date Code of Changed Product :1636

Description of Change (From) :

SOT323 package manufacturing site is FSC subcon which location in Korea, BOM as below

	L/F	Wire	Die attached	Molding compound
SOT323	Copper	Au	Eutectic	KTMC-1050GS

Description of Change (To) :

Qualify FSC Subcon which location in Chuzhou as the alternative manufacturing site for SOT323 package.

	L/F	Wire	Die attached	Molding compound
SOT323	Copper	Au	Eutectic	ELER-8-100HFE(green)

Reason for Change:

Manufacturing flexibility. Package outline drawings of the affected products remain unchanged. All of the affected products are fully compliant to all published data sheet and this change will have no impact on their electrical performance. Quality and reliability will remain at the highest standards already demonstrated with Fairchild's existing.



Affected Product(s):

2N7002KW	2N7002W	BSS138W
FJX1182YTF	FJX2907ATF	FJX3014RTF
FJX4006RTF		

Qualification Plan	Device	Package	Process	No. of Lots
Q20090412	FJX2222ATF	SOT323	SS-TR	3

Test Description:	Condition:	Standard :	Duration:	Results:
MSL1 Precondition	260C, 3 cycles	JESD22-A113		0/462
Temperature Humidity Bias	85%RH, 85C, 60V	JESD22-A101B	1000 hrs	0/231
Test				
High Temperature Reverse	150C, 60V	JESD22-A108	1000 hrs	0/231
Bias Test				
Power Cycle	Delta 100C, 2 Min	MIL-STD-750-	5000 cycles	0/231
	cycle	1036	-	
Temperature Cycle	-65C, 150C	JESD22-A104	500 cycles	0/231

Qualification Plan	Device	Package	Process	No. of Lots
Q20130070	FJX2222ATF	SOT323	SS-TR	1

Test Description:	Condition:	Standard :	Duration:	Results:
MSL1 Precondition	260C, 3 cycles	JESD22-A113		0/231
Temperature Humidity Bias	85%RH, 85C, 85%	JESD22-A101B	1000 hrs	0/77
Test	BV			
High Temperature Reverse	150C, 80% BV	JESD22-A108	1000 hrs	0/77
Bias Test				
High Temperature Storage	150C	JESD22-A103	1000 hrs	0/77
Life				
Power Cycle	Delta 100C, 2 Min	MIL-STD-750-	10000	0/77
	cycle	1036	cycles	
Temperature Cycle	-65C, 150C	JESD22-A104	500 cycles	0/77

Qualification Plan	Device	Package	Process	No. of Lots
Q20130070	BAT54SWT1G	SOT323	Schottky	1

Test Description:	Condition:	Standard :	Duration:	Results:
MSL1 Precondition	260C, 3 cycles	JESD22-A113		0/231
Temperature Humidity Bias Test	85%RH, 85C, 85% BV	JESD22-A101B	1000 hrs	0/77
High Temperature Reverse Bias Test	150C, 80% BV	JESD22-A108	1000 hrs	0/77
High Temperature Storage Life	150C	JESD22-A103	1000 hrs	0/77
Power Cycle	Delta 100C, 2 Min cycle	MIL-STD-750- 1036	10000 cycles	0/77
Temperature Cycle	-65C, 150C	JESD22-A104	500 cycles	0/77

Qualification Plan	Device	Package	Process	No. of Lots
Q20130070	BAV99WT1G	SOT323	Bipolar	1

Test Description:	Condition:	Standard :	Duration:	Results:
MSL1 Precondition	260C, 3 cycles	JESD22-A113		0/231
Temperature Humidity Bias	85%RH, 85C, 85%	JESD22-A101B	1000 hrs	0/77
lest	BV			
High Temperature Reverse	150C, 80% BV	JESD22-A108	1000 hrs	0/77
Bias Test				
High Temperature Storage	150C	JESD22-A103	1000 hrs	0/77
Life				
Power Cycle	Delta 100C, 2 Min	MIL-STD-750-	10000	0/77
	cycle	1036	cycles	
Temperature Cycle	-65C, 150C	JESD22-A104	500 cycles	0/77



Title : Qualification Report for PCN : P64EAAB

Date : May. 31, 2016

Affected devices :

С

Product	Customer Part NumberBBB	Drawing
2N7002KW	Y	Ν
2N7002W	Y	Ν
BSS138W	Y	Ν
FJX2907ATF	Y	Ν

С

0					
Product	Customer Part NumberBB	B Drawing			
FJX1182YTF	Y	Ν			
FJX2907ATF	Y	Ν			
FJX3014RTF	Y	Ν			
FJX4006RTF	Y	N			

С

Product	Customer Part Number	BBB	Drawing
FJX4006RTF		Y	Ν

Qualification Test Summary :

Qualification Plan	Device	Package	Process	No. of Lots
Q20090412	FJX2222ATF	SOT323	SS-TR	3

Test Description:	Condition:	Standard :	Duration:	Results:
MSL1 Precondition	260C, 3 cycles	JESD22-A113		0/462
Temperature Humidity Bias Test	85%RH, 85C, 60V	JESD22-A101B	1000 hrs	0/231
High Temperature Reverse Bias Test	150C, 60V	JESD22-A108	1000 hrs	0/231
Power Cycle	Delta 100C, 2 Min cycle	MIL-STD-750- 1036	5000 cycles	0/231
Temperature Cycle	-65C, 150C	JESD22-A104	500 cycles	0/231

Qualification PlanDevicePackageProcessNo. of LotsQ20130070FJX2222ATFSOT323SS-TR1

Test Description:	Condition:	Standard :	Duration:	Results:
MSL1 Precondition	260C, 3 cycles	JESD22-A113		0/231
Temperature Humidity Bias Test	85%RH, 85C, 85% BV	JESD22-A101B	1000 hrs	0/77
High Temperature Reverse Bias Test	150C, 80% BV	JESD22-A108	1000 hrs	0/77
High Temperature Storage Life	150C	JESD22-A103	1000 hrs	0/77
Power Cycle	Delta 100C, 2 Min cycle	MIL-STD-750- 1036	10000 cycles	0/77
Temperature Cycle	-65C, 150C	JESD22-A104	500 cycles	0/77

Qualification Plan Device Package Process No. of Lots Q20130070 BAT54SWT1G SOT323 Schottky 1

Test Description:	Condition:	Standard :	Duration:	Results:
MSL1 Precondition	260C, 3 cycles	JESD22-A113		0/231
Temperature Humidity Bias Test	85%RH, 85C, 85% BV	JESD22-A101B	1000 hrs	0/77
High Temperature Reverse Bias Test	150C, 80% BV	JESD22-A108	1000 hrs	0/77
High Temperature Storage Life	150C	JESD22-A103	1000 hrs	0/77
Power Cycle	Delta 100C, 2 Min cycle	MIL-STD-750- 1036	10000 cycles	0/77
Temperature Cycle	-65C, 150C	JESD22-A104	500 cycles	0/77

Qualification PlanDevicePackageProcessNo. of LotsQ20130070BAV99WT1GSOT323Bipolar1

Test Description:	Condition:	Standard :	Duration:	Results:
MSL1 Precondition	260C, 3 cycles	JESD22-A113		0/231
Temperature Humidity Bias Test	85%RH, 85C, 85% BV	JESD22-A101B	1000 hrs	0/77
High Temperature Reverse Bias Test	150C, 80% BV	JESD22-A108	1000 hrs	0/77
High Temperature Storage Life	150C	JESD22-A103	1000 hrs	0/77
Power Cycle	Delta 100C, 2 Min cycle	MIL-STD-750- 1036	10000 cycles	0/77
Temperature Cycle	-65C, 150C	JESD22-A104	500 cycles	0/77

The selection methodology of qualification vehicles is aligned with JESD47 and if automotive devices are impacted by the PCN the selection of qualification vehicles is also align with the requirements in AEC-Q100 or AEC-Q101

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